

THE SOFT X-RAY INDUCED CHEMISTRY OF CO AND CH₃OH IN WATER ICE STUDIED BY NEXAFS

C. Laffon¹, J. Lasne¹, F. Bournel¹, K. Schulte², S. Lacombe³, Ph. Parent¹

¹*Laboratoire de Chimie-Physique, Matière et Rayonnement, Université Pierre-et-Marie Curie (UPMC-Univ Paris 06) and CNRS (UMR 7614), 11 rue Pierre-et-Marie-Curie, 75231 PARIS CEDEX 05-France.*

²*MAX-lab, Lund University, PO Box 118, S-221 00 LUND-Sweden.*

³*Laboratoire des Collisions Atomiques et Moléculaires, CNRS- LCAM, 91405 ORSAY CEDEX-France. Université Paris Sud 11- Bât 351, 91405 ORSAY CEDEX-France.*

The irradiation of organic molecules in condensed water is an important process in a wide variety of scientific areas, from the chemistry of the interstellar space medium[1] to radiobiology.[2] Aiming at characterizing these reactions at a molecular scale, we have recently developed the use of the Near-Edge X-ray Absorption Spectroscopy (NEXAFS) for studying irradiation of icy solutions. In this work, the soft X-ray induced chemistry of H₂O, CO and CH₃OH and the effects of the water and nitric acid hydrate (HNO₃.1.65H₂O) matrix on the photochemistry of CO and CH₃OH have been investigated. For pure H₂O, CO and CH₃OH ices, the destruction rates are strongly limited by back reactions, leading to strikingly high survival rates of these molecules upon the harsh irradiation conditions to which they were submitted. We also evidence the interplay between the photochemical reactions of CO and CH₃OH and those of the matrix. The OH and O radicals released by the photolysis of H₂O and HNO₃ react with the CO and CH₃OH and their fragments, considerably reducing the survival rates, especially in presence of nitric acid, and dramatically enhancing the formation of CO₂ at the expense of CO. Because NEXAFS spectroscopy allows identifying which reactions are important among those possible, it emerges a simple picture of the photochemical routes of CO and CH₃OH in the H₂O and HNO₃/H₂O environments.

[1] A. G. G. M. Tielens and W. Hagen, *Astron. Astrophys.*, **114**, 245 (1982)

[2] K. Fujii, N. Shikazono and A. Yokoya, *J. Phys. Chem. B*, **113**, 16007 (2009).